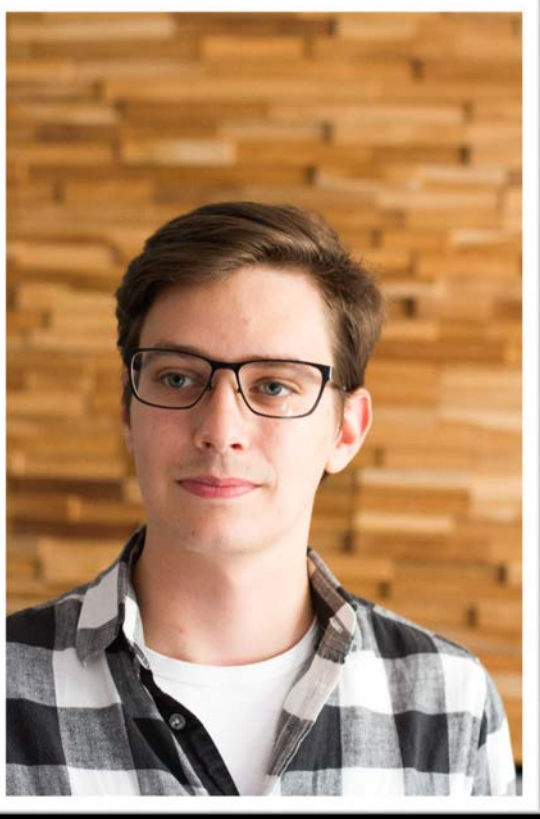


# Optimized design for on-chip Fabry-Pérot resonators

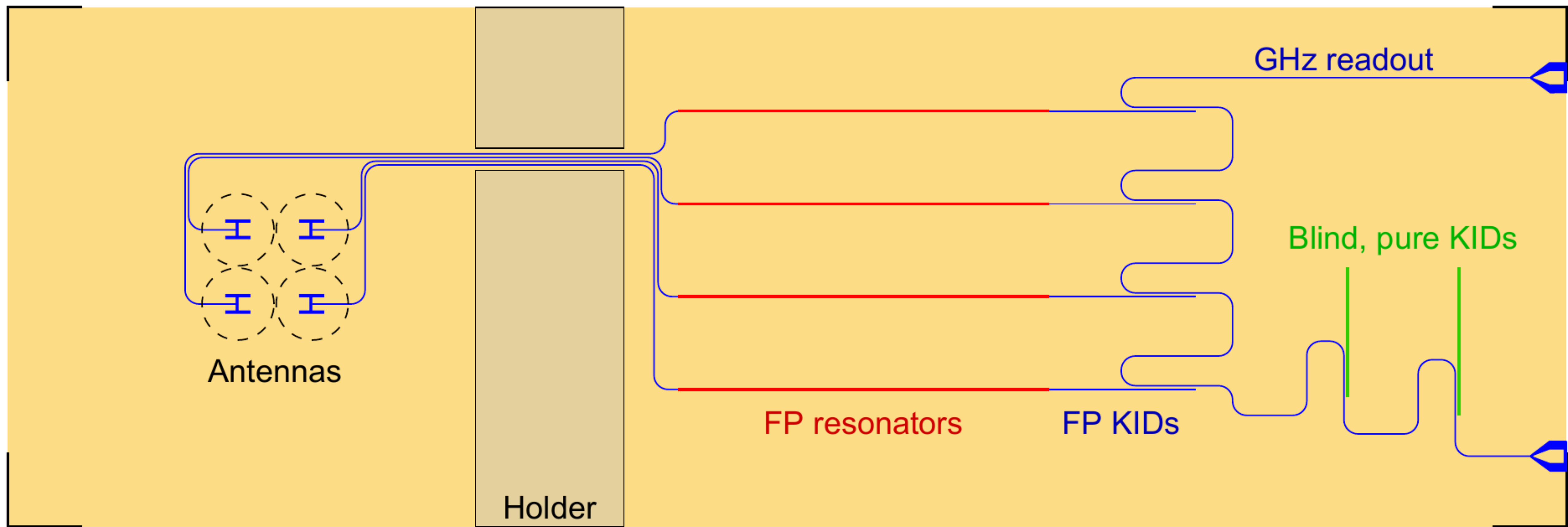
K. Kouwenhoven<sup>1</sup>, S. Hähle<sup>1,2</sup>, D. Thoen<sup>1</sup>, V. Murugesan<sup>2</sup>, and J. J. A. Baselmans<sup>1,2</sup>



<sup>1</sup> Terahertz Sensing group, Delft University of Technology, Delft, The Netherlands

<sup>2</sup> Netherlands Institute for Space Research, SRON, Utrecht, The Netherlands

K.Kouwenhoven@tudelft.nl - terahertz.tudelft.nl



## Motivation

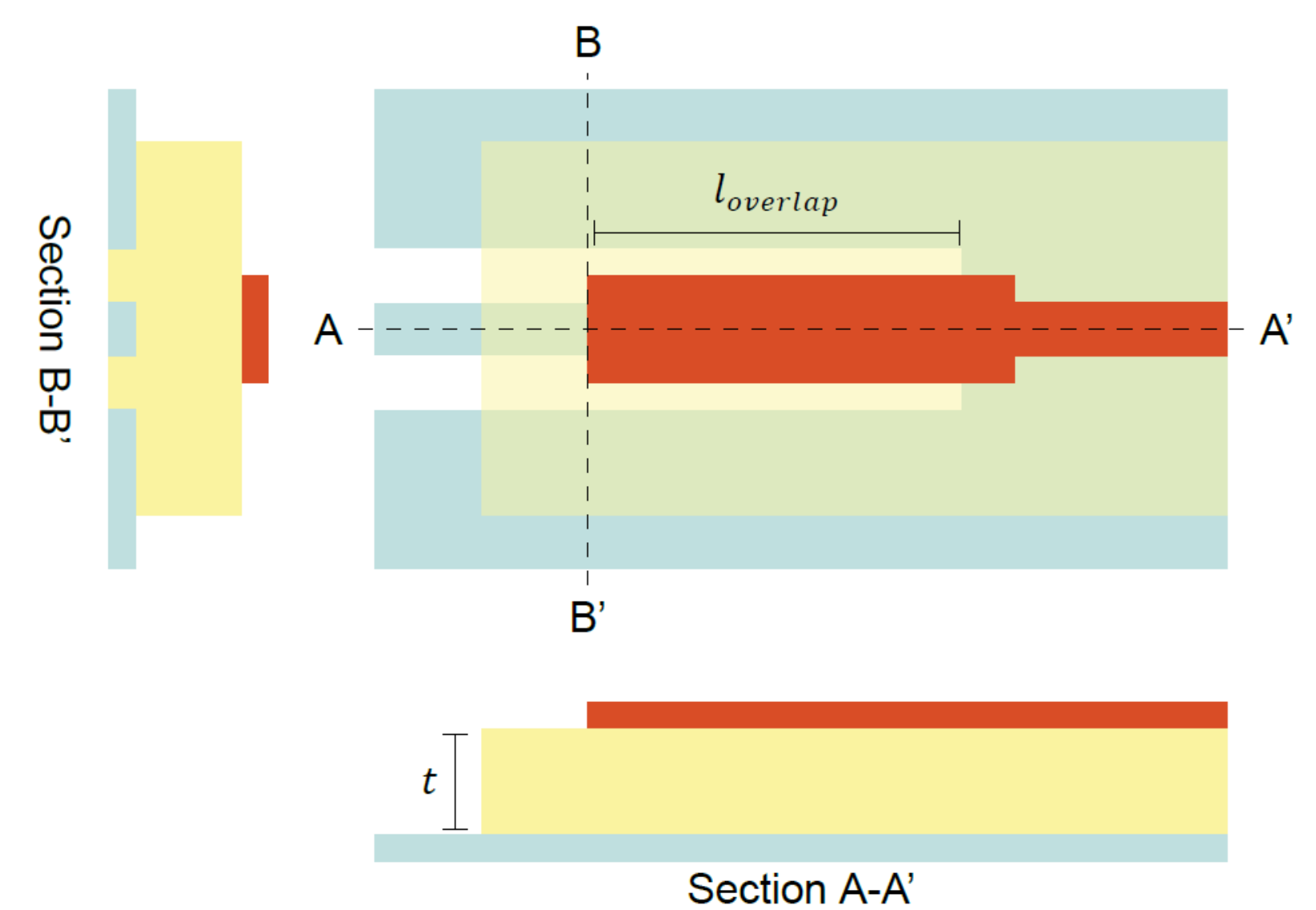
- On-chip spectrometers, such as DESHIMA, require transmission lines with  $\tan\delta < 10^{-4} \rightarrow Q_i > 10^4$ .
- Dielectric losses unknown under DESHIMA operating conditions.
- Design a lab-on-a-chip concept based on Fabry-Pérot resonators to measure the dielectric losses for:
  - Sub-K temperatures.
  - 300 GHz - 1.1 THz.
  - $Q_i$  from 100 to  $10^5$ .

### DESHIMA:

Talk [160] Fr. 16:30 by A. Endo  
Poster [236-259] by A. Pascual Laguna

## CPW to microstrip couplers

- Couples microstrip resonator to CPW feed- and readout lines.
- $l_{overlap}$  sets  $|S_{21,coupler}|$  and  $\min|S_{21}| \rightarrow$  full curve approach.
- Couples directly to the shorted MKID line.



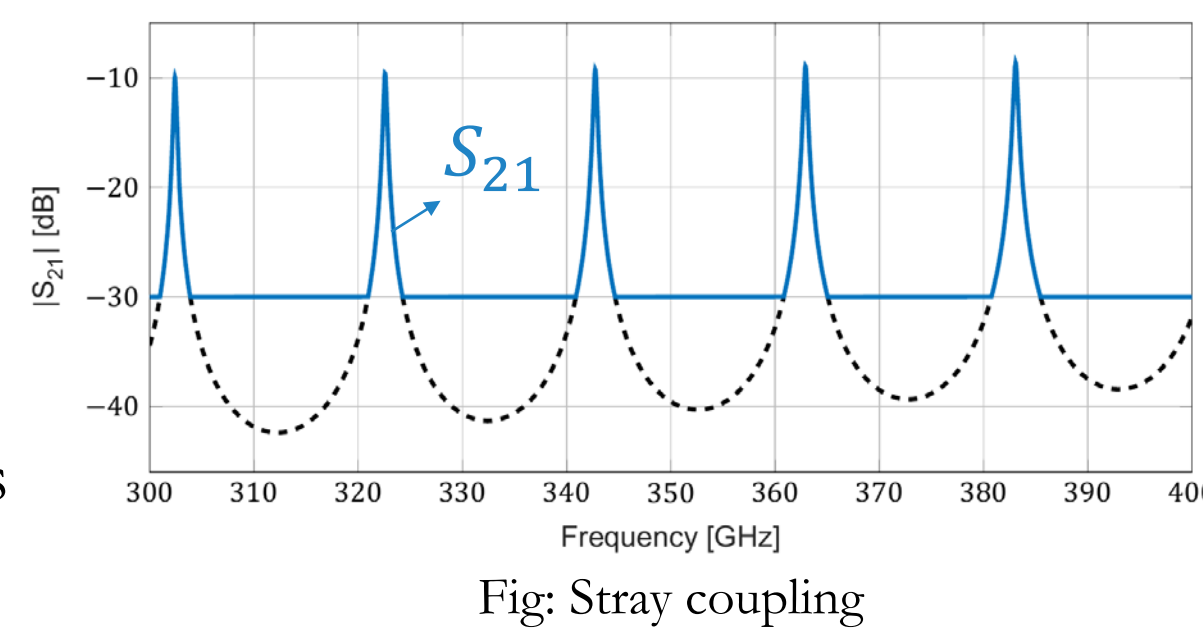
## Measuring the losses $Q_i$

$Q_l$ : loaded quality factor  $\rightarrow$  shape of the peak  
 $Q_c$ : coupling Q-factor  
 $Q_i$ : intrinsic loss Q-factor =  $(\tan\delta)^{-1}$

$$\frac{1}{Q_l} = \frac{1}{Q_c} + \frac{1}{Q_i}$$

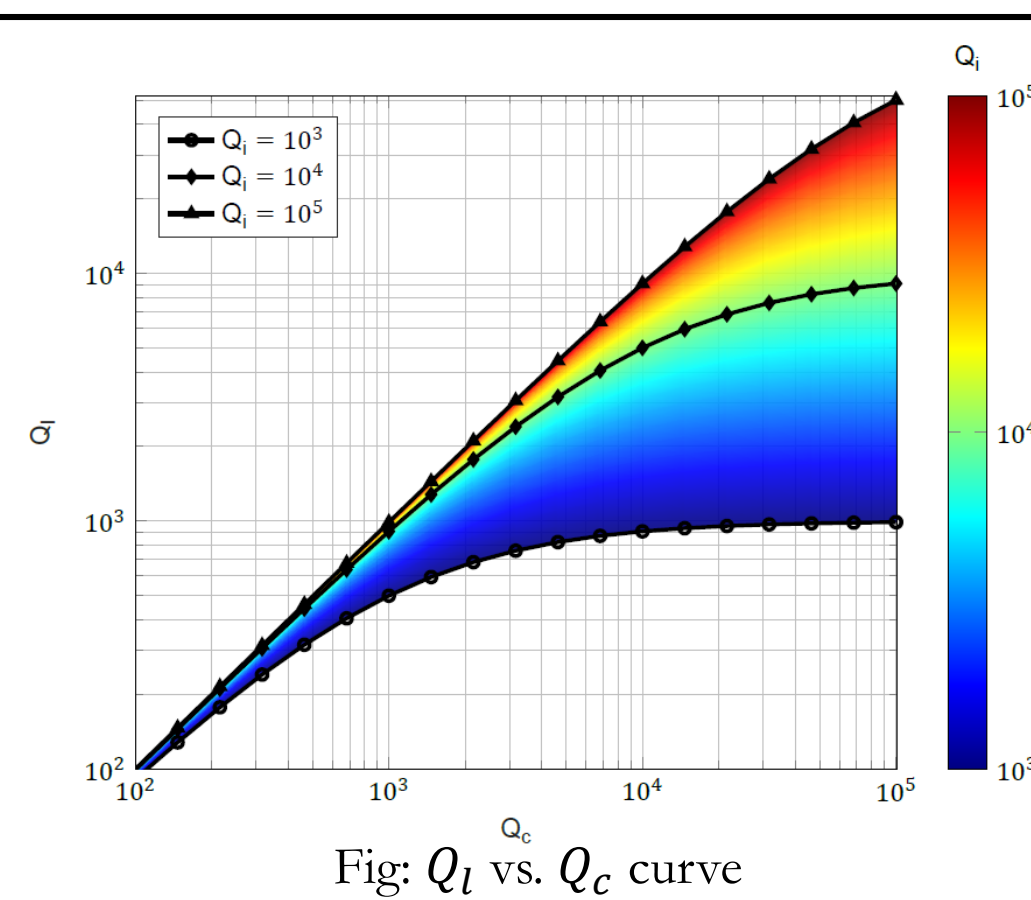
- Problem: realised  $Q_c$  unknown due to fabrication uncertainties.
- $Q_i$  limited approach:
  - Design resonator such that  $Q_c \gg Q_i \rightarrow Q_l \approx Q_i$ .
  - Limited frequency resolution of the source prohibits adequate sampling of the high  $Q_l$  FP peak  $\rightarrow$  Not usable for high  $Q_i$  dielectrics.
- Full  $|S_{21}|$  curve approach:
  - Relative peak height gives  $Q_c$ .
  - Not limited by frequency resolution of the source!
  - Limited by stray coupling  $\rightarrow$  part of the curve is lost

**Measurement set-up:**  
Poster [181-147] by S. Hähle



## Optimized FP Design

- Four independent resonators on a chip:
  - Each with different  $Q_c$ .
  - Probe the  $Q_i$  vs.  $Q_c$  curve.
  - Redundancy.
- Design resonators for full curve measurements:
  - Ensure entire  $|S_{21}|$  curve lies above stray coupling limit.
  - The coupler sets  $\min|S_{21}|$ .
  - Desired  $Q_c$  can then be obtained by changing the length of the resonator  $\rightarrow$  change mode number  $n$ .

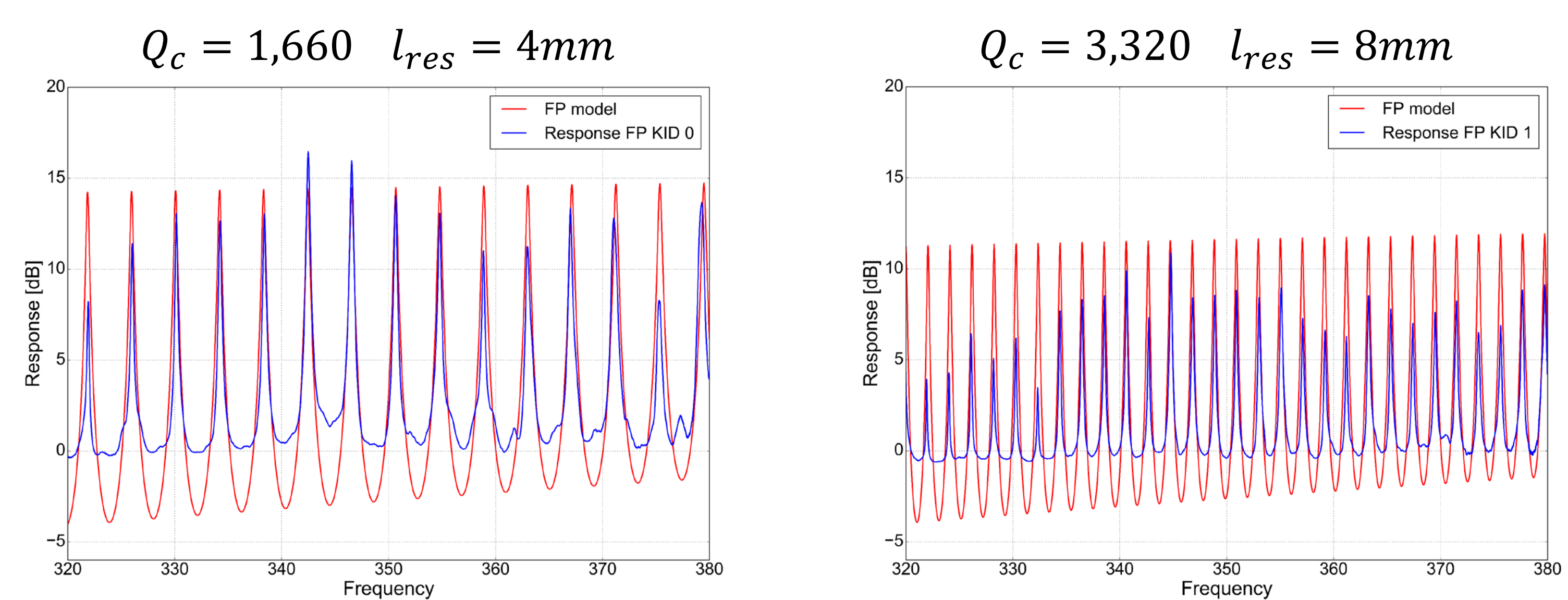


$$Q_c = \frac{n\pi}{|S_{21,coupler}|^2} \quad n = \frac{f_n}{f_0} \quad f_0 = \frac{c_0}{2l_{resonator}\sqrt{\epsilon_{r,eff}}}$$

### Advantages:

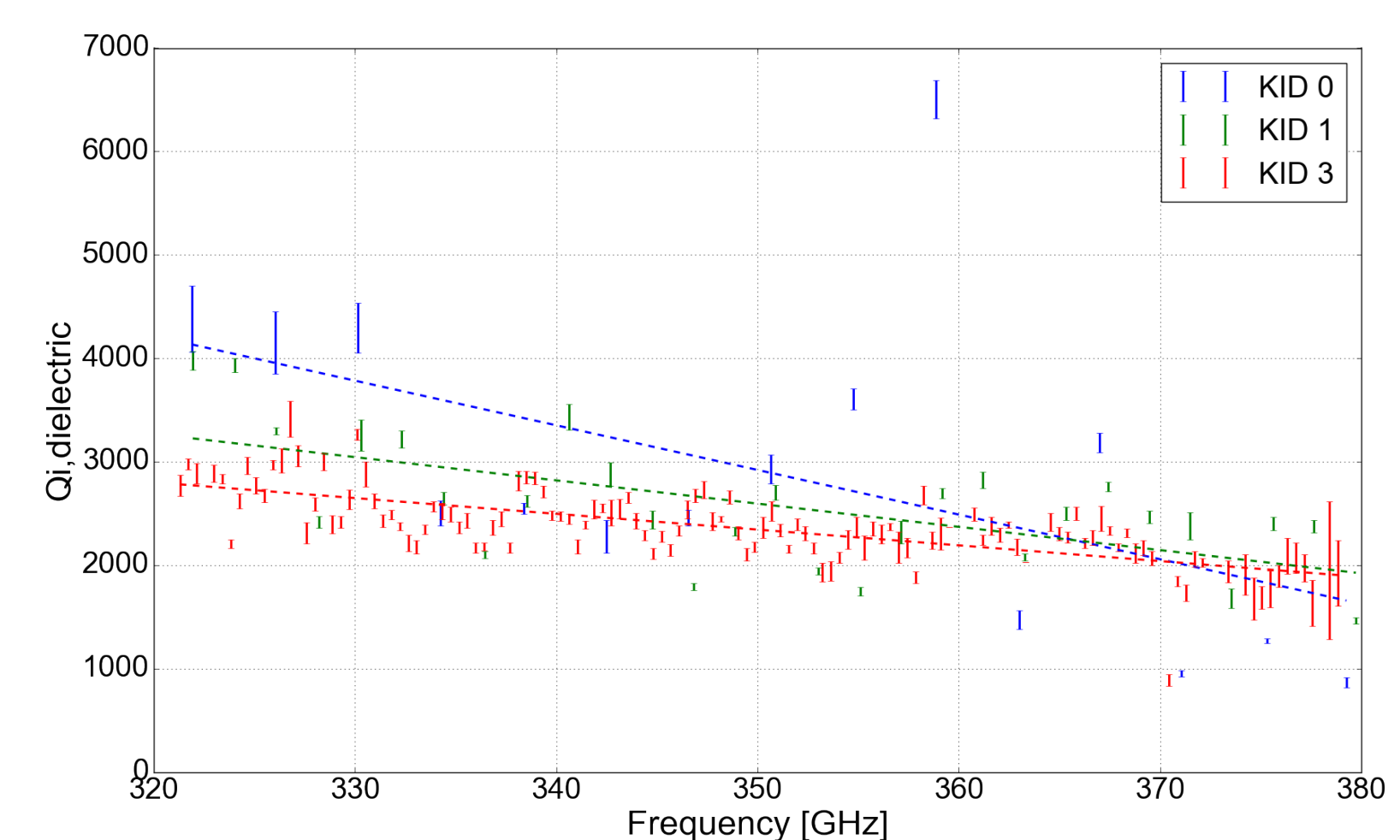
- Full curve approach enables measurement of  $Q_c$ !
- Works for entire  $Q_i$  range of 100 to  $10^5$ !
- Not limited by frequency resolution of the source!
- 4 resonators on a single chip!

## Modelled vs. Measured Response



## Measured $Q_i$

- Able to measure losses of a microstrip at 300 – 400 GHz!
  - $Q_i \sim 2000 - 3000$
  - $\tan\delta \sim 0.33 \times 10^{-3} - 0.5 \times 10^{-3}$
- PECVD deposited a-Si.
- Sputter deposited NbTiN.



## Conclusion and Outlook

- Measured losses of a superconducting microstrip at sub-K temperatures and 300 - 400 GHz!
- Good match between modelled and measured FP response!
- Measured losses higher than expected.
  - Likely due to low NbTiN film quality  $\rightarrow$  new fabrication run.
- Future work:
  - Additional structures for microwave (4 – 8 GHz) measurements.
  - Different dielectrics, deposited in-house  $\rightarrow$  Study effect of deposition conditions.